

SATA Slim

3SE Series

Customer: _____

Customer

Part

Number: _____

Innodisk

Part

Number: _____

Innodisk

Model Name: _____

Date: _____

Innodisk Approver	Customer Approver

**Total Solution For
Industrial Flash Storage**

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REVISION HISTORY

Revision	Description	Date
Preliminary	First Released	Sep., 2013
Rev 1.0	Update performance	Mar., 2014
Rev 1.1	Modify TBW based on NAND Flash specifications	Jan., 2015
Rev 1.2	Add TRIM note Modify “Code 15 th (Internal control)” to B Update RoHS report to 2019 version	Jun., 2019
Rev 1.3	Update power consumption	May., 2020

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1. Product Overview

1.1 Introduction of Innodisk SATA Slim 3SE

Innodisk SATA Slim 3SE is designed with standard SATA interface (7+15 SATA connector), which could support most platforms with standard SATA port. Besides, with its smaller dimension, SATA Slim 3SE is an alternative solution of 2.5" SSD for those embedded system that may have mechanical and space concerns. SATA Slim 3SE operates under SATA III (6.0Gb/s) protocol with good performance.

SATA Slim 3SE is also suitable in industrial field. It effectively reduces the booting time of operation system and the power consumption is less than hard disk drive (HDD). SATA Slim 3SE is compatible with ATA protocol, no additional drivers are required, and the SATA Slim 3SE can be configured as a boot device or data storage device.

CAUTION *TRIM must be enabled.*

TRIM enables SSD's controller to skip invalid data instead of moving. It can free up significant amount of resources, extends the lifespan of SSD by reducing erase, and write cycles on the SSD. Innodisk's handling of garbage collection along with TRIM command improves write performance on SSDs.

1.2 Product View and Models

Innodisk SATA Slim 3SE is available in follow capacities within SLC flash ICs.

SATA Slim 3SE 04GB

SATA Slim 3SE 32GB

SATA Slim 3SE 08GB

SATA Slim 3SE 64GB

SATA Slim 3SE 16GB

SATA Slim 3SE 128GB

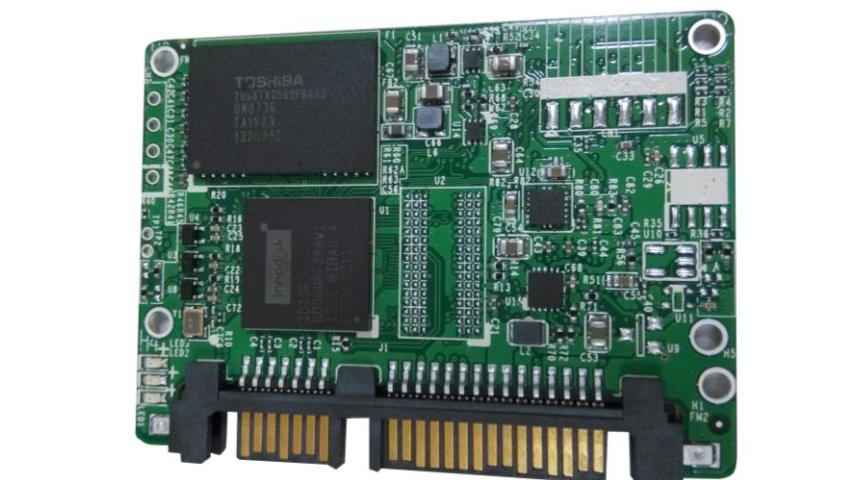


Figure 1: Innodisk SATA Slim 3SE

1.3 SATA Interface

Innodisk SATA Slim 3SE support SATA III interface, and compliant with Serial ATA Gen 1, Gen 2 and Gen 3 specification (Gen 3 supports 1.5Gbps /3.0Gbps/6.0Gbps data rate). SATA connector uses a 7-pin signal segment and a 15-pin power segment.

1.4 Capacity

Innodisk SATA Slim 3SE provides unformatted 4GB, 8GB, 16GB, 32GB, 64GB and 128GB capacities within SLC Flash IC.

1.5 MO-297 Form Factor

SATA Slim 3SE has a compact design 54.0mm (W) x 39.0mm (L) x 4.0mm (H) without metal material case, and is easy for installation.

2. Product Specifications

2.1 Capacity and Device Parameters

Innodisk SATA Slim 3SE device parameters are shown in Table 1.

Table 1: Device parameters

Capacity	LBA	Cylinders	Heads	Sectors	User Capacity(MB)
4GB	7835184	7773	16	63	3,826
8GB	15649200	15255	16	63	7,641
16GB	31277232	16383	16	63	15,272
32GB	62533296	16383	16	63	30,533
64GB	125045424	16383	16	63	61,057
128GB	250069680	16383	16	63	122,104

2.2 Performance

Burst Transfer Rate: 6.0Gbps

Table 2: Performance

Capacity	4GB	8GB	16GB	32GB	64GB	128GB
Sequential Read (max.)	250 MB/sec	370 MB/sec	470 MB/sec	480 MB/sec	480 MB/sec	460 MB/sec
Sequential Write (max.)	50 MB/sec	110 MB/sec	230 MB/sec	250 MB/sec	410 MB/sec	360 MB/sec

Note: Base on CrystalDiskMark 3.01 with file size 1000MB

2.3 Electrical Specifications

2.3.1 Power Requirement

Table 3: Innodisk SATA Slim 3SE Power Requirement

Item	Symbol	Rating	Unit
Input voltage	V _{IN}	+5 DC +- 5%	V

2.3.2 Power Consumption

Table 4: Power Consumption

Mode	Power Consumption (mA)
Read	266 (max.)
Write	362 (max.)
Idle	139 (max.)

* Target: SATA Slim 3SE 128GB

2.4 Environmental Specifications

2.4.1 Temperature Ranges

Table 5: Temperature range for SATA Slim 3SE

Temperature	Range
Operating	Standard Grade: 0°C to +70°C
	Industrial Grade: -40°C to +85°C
Storage	-55°C to +95°C

2.4.2 Humidity

Relative Humidity: 10-95%, non-condensing

2.4.3 Shock and Vibration

Table 6: Shock/Vibration Testing for SATA Slim 3SE

Reliability	Test Conditions	Reference Standards
Vibration	7 Hz to 2K Hz, 20G, 3 axes	IEC 68-2-6
Mechanical Shock	Duration: 0.5ms, 1500 G, 3 axes	IEC 68-2-27

2.4.4 Mean Time between Failures (MTBF)

Table 7 summarizes the MTBF prediction results for various SATA Slim 3SE configurations. The analysis was performed using a RAM Commander™ failure rate prediction.

- **Failure Rate:** The total number of failures within an item population, divided by the total number of life units expended by that population, during a particular measurement interval under stated condition.
- **Mean Time between Failures (MTBF):** A basic measure of reliability for repairable items: The mean number of life units during which all parts of the item perform within their specified limits, during a particular measurement interval under stated conditions.

Table 7: SATA Slim 3SE MTBF

Product	Condition	MTBF (Hours)
Innodisk SATA Slim 3SE	Telcordia SR-332 GB, 25°C	>3,000,000

2.5 CE and FCC Compatibility

SATA Slim 3SE conforms to CE and FCC requirements.

2.6 RoHS Compliance

SATA Slim 3SE is fully compliant with RoHS directive.

2.7 Reliability

Parameter	Value
Read Cycles	Unlimited Read Cycles
Wear-Leveling Algorithm	Support
Bad Blocks Management	Support
Error Correct Code	Support
TBW (Unit: TB)	
4GB	216 (Sequential Write)
8GB	432 (Sequential Write)
16GB	864 (Sequential Write)
32GB	1728 (Sequential Write)
64GB	3456 (Sequential Write)
128GB	6912 (Sequential Write)

2.8 Transfer Mode

SATA Slim 3SE support following transfer mode:

Serial ATA III 6.0Gbps

Serial ATA II 3.0Gbps

Serial ATA I 1.5Gbps

2.9 Pin Assignment

Innodisk SATA Slim 3SE uses a standard SATA pin-out. See Table 8 for SATA Slim 3SE pin assignment.

Table 8: Innodisk SATA Slim 3SE Pin Assignment

Name	Type	Description
S1	GND	NA
S2	A+	Differential Signal Pair A
S3	A-	
S4	GND	NA
S5	B-	Differential Signal Pair B
S6	B+	

2.12 Seek Time

Innodisk SATA Slim 3SE is not a magnetic rotating design. There is no seek or rotational latency required.

2.13 Hot Plug

The SSD support hot plug function and can be removed or plugged-in during operation. User has to avoid hot plugging the SSD which is configured as boot device and installed operation system.

Surprise hot plug : The insertion of a SATA device into a backplane (combine signal and power) that has power present. The device powers up and initiates an OOB sequence.

Surprise hot removal: The removal of a SATA device from a powered backplane, without first being placed in a quiescent state.

2.14 NAND Flash Memory

Innodisk SATA Slim 3SE uses Single Level Cell (SLC) NAND flash memory, which is non-volatility, high reliability which has 100,000 program/erase times and high speed memory storage.

3. Theory of Operation

3.1 Overview

Figure 2 shows the operation of Innodisk SATA Slim 3SE from the system level, including the major hardware blocks.

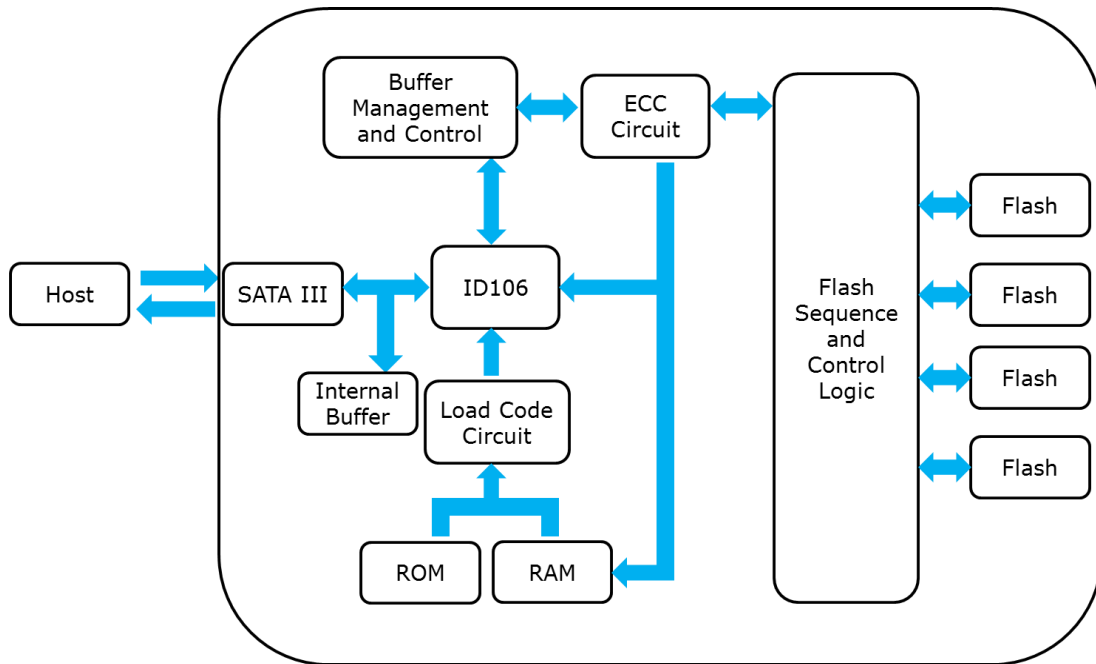


Figure 2: Innodisk SATA Slim 3SE Block Diagram

Innodisk SATA Slim 3SE integrates a SATA III controller and NAND flash memories. Communication with the host occurs through the host interface, using the standard ATA protocol. Communication with the flash device(s) occurs through the flash interface.

3.2 SATA III Controller

Innodisk SATA Slim 3SE is designed with ID 106, a SATA III 6.0Gbps (Gen. 3) controller. The Serial ATA physical, link and transport layers are compliant with Serial ATA Gen 1, Gen 2 and Gen 3 specification (Gen 3 supports 1.5Gbps/3.0Gbps/6.0Gbps data rate). The controller has 4 channels for flash interface.

3.3 Error Detection and Correction

Highly sophisticated Error Correction Code algorithms are implemented. The ECC unit consists of the Parity Unit (parity-byte generation) and the Syndrome Unit (syndrome-byte computation). This unit implements an algorithm that can correct 40 bits per 1024 bytes in an ECC block. Code-byte generation during write operations, as well as error detection during read operation, is

implemented on the fly without any speed penalties.

3.4 Wear-Leveling

Flash memory can be erased within a limited number of times. This number is called the **erase cycle limit** or **write endurance limit** and is defined by the flash array vendor. The erase cycle limit applies to each individual erase block in the flash device.

Innodisk SATA Slim 3SE uses a static wear-leveling algorithm to ensure that consecutive writes of a specific sector are not written physically to the same page/block in the flash. This spreads flash media usage evenly across all pages, thereby extending flash lifetime.

3.5 Bad Blocks Management

Bad Blocks are blocks that contain one or more invalid bits whose reliability are not guaranteed. The Bad Blocks may be presented while the SSD is shipped, or may develop during the life time of the SSD. When the Bad Blocks is detected, it will be flagged, and not be used anymore. The SSD implement Bad Blocks management, Bad Blocks replacement, Error Correct Code to avoid data error occurred. The functions will be enabled automatically to transfer data from Bad Blocks to spare blocks, and correct error bit.

3.6 Power Cycling

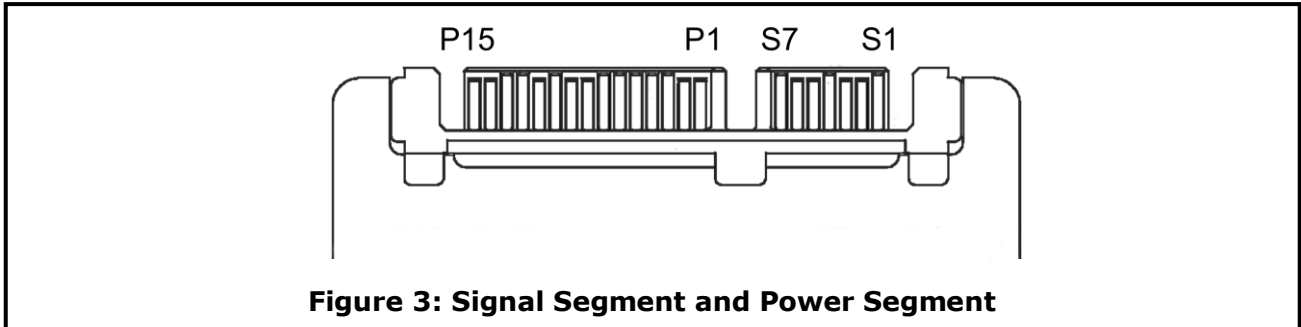
Innodisk's power cycling management is a comprehensive data protection mechanism that functions before and after a sudden power outage to SSD. Low-power detection terminates data writing before an abnormal power-off, while table-remapping after power-on deletes corrupt data and maintains data integrity. Innodisk's power cycling provides effective power cycling management, preventing data stored in flash from degrading with use.

3.7 Garbage Collection

Garbage collection is used to maintain data consistency and perform continual data cleansing on SSDs. It runs as a background process, freeing up valuable controller resources while sorting good data into available blocks, and deleting bad blocks. It also significantly reduces write operations to the drive, thereby increasing the SSD's speed and lifespan.

4. Installation Requirements

4.1 SATA Slim 3SE Pin Directions



4.2 Electrical Connections for SATA Slim 3SE

A Serial ATA device may be either directly connected to a host or connected to a host through a cable. For connection via cable, the cable should be no longer than 1meter. The SATA interface has a separate connector for the power supply. Please refer to the pin description for further details.

4.3 Device Drive

No additional device drives are required. Innodisk SATA Slim 3SE can be configured as a boot device.

5. Part Number Rule

CODE	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20
	D	E	S	L	M	-	3	2	G	D	0	6	S	C	B	Q	B	-	X	X
Description	Disk	SATA Slim 3SE					Capacity			Category			Flash Mode	Operation Temp.	Internal Control	CH.	Flash	-	Customized Code	
Definition																				
Code 1st (Disk)												Code 13th (Flash Mode)								
D : Disk												S: Synchronous flash								
Code 2nd ~ 5th (Form Factor)												Code 14th (Operation Temperature)								
ESLM: SATA Slim 3SE												C: Standard Grade (0°C ~ +70°C)								
Code 7th ~ 9th (Capacity)												Code 15th (Internal control)								
04G: 4GB												Code 16th (Channel of data transfer)								
08G: 8GB																				
16G: 16GB												D: Dual Channels								
32G: 32GB												Q: Quad Channels								
64G: 64GB												Code 17th (Flash Type)								
A28: 128GB												B: Toshiba SLC								
Code 10th ~ 12th (Series)												Code 19th ~ 20th (Customized Code)								
D06: ID106																				

Appendix

RoHS 自我宣告書 (RoHS Declaration of Conformity)

Manufacturer Product: All Innodisk EM Flash and Dram products

- 一、 宜鼎國際股份有限公司（以下稱本公司）特此保證售予貴公司之所有產品，皆符合歐盟 2011/65/EU 及 (EU) 2015/863 關於 RoHS 之規範要求。
Innodisk Corporation declares that all products sold to the company, are complied with European Union RoHS Directive (2011/65/EU) and (EU) 2015/863 requirement.
- 二、 本公司同意因本保證書或與本保證書相關事宜有所爭議時，雙方宜友好協商，達成協議。
Innodisk Corporation agrees that both parties shall settle any dispute arising from or in connection with this Declaration of Conformity by friendly negotiations.
- 三、 本公司聲明我們的產品符合 RoHS 指令的附件中 (7a)、(7c-1) 允許豁免。
We declare, our products permitted by the following exemptions specified in the Annex of the RoHS directive.
- ※ (7a) Lead in high melting temperature type solders (i.e. lead-based alloys containing 85% by weight or more lead).
- ※ (7C-1) Electrical and electronic components containing lead in a glass or ceramic other than dielectric ceramic in capacitors, e.g. piezoelectric devices, or in a glass or ceramic matrix compound.

Name of hazardous substance	Limited of RoHS ppm (mg/kg)
鉛 (Pb)	< 1000 ppm
汞 (Hg)	< 1000 ppm
鎘 (Cd)	< 100 ppm
六價鉻 (Cr 6+)	< 1000 ppm
多溴聯苯 (PBBs)	< 1000 ppm
多溴二苯醚 (PBDEs)	< 1000 ppm
鄰苯二甲酸二(2-乙基己基)酯 (DEHP)	< 1000 ppm
鄰苯二甲酸丁酯苯甲酯 (BBP)	< 1000 ppm
鄰苯二甲酸二丁酯 (DBP)	< 1000 ppm
鄰苯二甲酸二異丁酯 (DIBP)	< 1000 ppm

立保證書人 (Guarantor)

Company name 公司名稱： Innodisk Corporation 宜鼎國際股份有限公司

Company Representative 公司代表人： Randy Chien 簡川勝

宜鼎國際股份有限公司

Innodisk Corporation

Company Representative Title 公司代表人職稱：Chairman 董事長

Date 日期：2018 / 07 / 01





宜鼎國際股份有限公司
Innodisk Corporation
REACH Declaration

Tel: (02) 7703-3000 Fax: (02) 7703-3555 Internet: <http://www.innodisk.com/>

We hereby confirm that the product(s) delivered to

Innodisk P/N	Description
All Innodisk EM FLASH Products	

- contain(s) **no** hazardous substances or constituents exceeding the defined threshold 0.1 % by weight in homogenous material if not otherwise specified, as described in the candidate list table currently including 197 substances and shown on the ECHA website (<http://echa.europa.eu/de/candidate-list-table>).
- contain(s) one or more hazardous substances or constituents exceeding 0.1 % by weight in homogenous material if not otherwise specified in candidate list table. Where the threshold value is exceeded, the substances in question are to be declared in accompanying Appendix A.
- Comply with REACH Annex XVII.

Guarantor

Company name 公司名稱： Innodisk Corporation 宜鼎國際股份有限公司

Company Representative 公司代表人： Randy Chien 簡川勝

Company Representative Title 公司代表人職稱： Chairman 董事長

Date 日期： 2019 / 01 / 31



Certificate

Issue Date: December 18, 2013
Ref. Report No. ISL-13HE356CE

Product Name : SATA Slim 3SE / SATA Slim 3SE-P
Model(s) : DESLM-XXXD06*#%※ &; DESLM-XXXD67*#%※ &
Responsible Party : Innodisk Corporation
Address : 9F, No. 100, Sec. 1 Xintai 5th Rd., Xizhi City, Taipei 221, Taiwan

We, **International Standards Laboratory**, hereby certify that:

The device bearing the trade name and model specified above has been shown to comply with the applicable technical standards as indicated in the measurement report and was tested in accordance with the measurement procedures specified in European Council Directive- EMC Directive 2004/108/EC. The device was passed the test performed according to :



Standards:

- EN 55022: 2010 and CISPR 22: 2008 (modified)
- EN 61000-3-2: 2006+A1:2009 +A2:2009 and IEC 61000-3-2: 2005+A1:2008 +A2:2009
- EN 61000-3-3: 2008 and IEC 61000-3-3: 2008
- EN 55024: 2010 and CISPR 24: 2010
- EN 61000-4-2: 2009 and IEC 61000-4-2: 2008
- EN 61000-4-3: 2006+A1: 2008 +A2: 2010 and IEC 61000-4-3:2006+A1: 2007+A2: 2010
- EN 61000-4-4: 2004 +A1:2010 and IEC 61000-4-4: 2004 +A1:2010

I attest to the accuracy of data and all measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

International Standards Laboratory

Jim Chu
Jim Chu / Director

Hsi-Chih LAB:
No. 65, Gu Dai Keng St., Hsichih District,
New Taipei City 22179, Taiwan
Tel: 886-2-2646-2550; Fax: 886-2-2646-4641



Certificate

Issue Date: December 18, 2013

Ref. Report No. ISL-13HE356FB

Product Name : SATA Slim 3SE / SATA Slim 3SE-P
 Model(s) : DESLM-XXXX06*#%&; DESLM-XXXX067*#%&
 Applicant : Innodisk Corporation
 Address : 9F, No. 100, Sec. 1 Xintai 5th Rd., Xizhi City, Taipei 221, Taiwan

We, International Standards Laboratory, hereby certify that:

The device bearing the trade name and model specified above has been shown to comply with the applicable technical standards as indicated in the measurement report and was tested in accordance with the measurement procedures specified. (refer to Test Report if any modifications were made for compliance).



Standards:

FCC CFR Title 47 Part 15 Subpart B: 2010- Section 15.107 and 15.109

ANSI C63.4-2009

Industry Canada Interference-Causing Equipment Standard ICES-003 Issue 5: 2012

Class B

I attest to the accuracy of data and all measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

International Standards Laboratory

Jim Chu
Jim Chu / Director

Hsi-Chih LAB:

No. 65, Gu Dai Keng St., Hsichih District,
New Taipei City 22179, Taiwan

Tel: 886-2-2646-2550; Fax: 886-2-2646-4641

